- '154 is Ideal for High-Performance Memory Decoding
- Decodes 4 Binary-Coded Inputs into One of 16 Mutually Exclusive Outputs
- Performs the Demultiplexing Function by Distributing Data From One Input Line to Any One of 16 Outputs
- Input Clamping Diodes Simplify System Design
- High Fan-Out, Low-Impedance, Totem-Pole Outputs
- Fully Compatible with Most TTL and MSI Circuits

TYPICAL AVERAGE
PROPAGATION DELAY
3 LEVELS OF LOGIC STROBE

TYPICAL POWER DISSIPATION

23 ns

19 ns

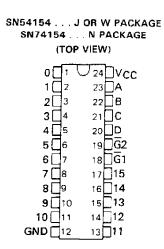
170 mW

description

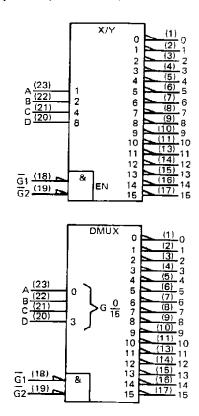
Each of these monolithic, 4-line-to-16-line decoders utilizes TTL circuitry to decode four binary-coded inputs into one of sixteen mutually exclusive outputs when both the strobe inputs, $\overline{G}1$ and $\overline{G}2$, are low. The demultiplexing function is performed by using the 4 input lines to address the output line, passing data from one of the strobe inputs with the other strobe input low. When either strobe input is high, all outputs are high. These demultiplexers are ideally suited for implementing high-performance memory decoders. For ultra-high speed systems, SN54S138/SN74S138 and SN54S139/SN74S139 are recommended.

These circuits are fully compatible for use with most other TTL circuits. All inputs are buffered and input clamping diodes are provided to minimize transmission-line effects and thereby simplify system design.

The SN54154 is characterized for operation over the full military temperature range of $-55\,^{\circ}\text{C}$ to 125 $^{\circ}\text{C}$. The SN74154 is characterized for operation from 0 $^{\circ}\text{C}$ to 70 $^{\circ}\text{C}$.



logic symbols (alternatives)† _



¹These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

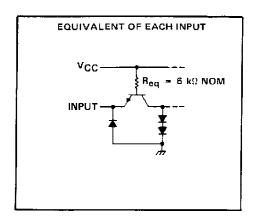


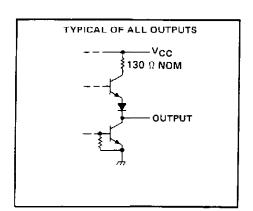
FUNCTION TABLE

INPUTS												OUT	PUTS						-		
Ĝ1	G2	D	C	8	А	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15
L	L	L	L	L	L	L	н	н	Н	н	Н	н	Н	н	Н	н	Н	Н	Н	Н	Н
L	L	L	L	L	H	Н	L	14	н	н	н	н	н	н	н	Н	H	н	Н	н	Н
L	L	L	L	Н	L	н	Н	L	Н	Н	Н	н	Н	Н	Н	Н	Н	н	н	Н	Н
L	L	l.	l.	Н	Н	Н	Н	Н	Ĺ	Н	Н	н	Н	Н	Н	Н	н	H	н	н	н
L	L	L	н	L	L	Н	Н	Н	Н	L	н	Н	H	Н	Н	Н	н	Н	Н	Н	Н
L	L	L	Н	L	Н	Н	Н	Н	Н	H	L	Н	н	Н	Н	Н	н	H	Н	н	H
L	L	L	Н	Н	L	н	H	H	Н	Н	++	L	+1	Н	Н	Н	Н	н	Н	Н	Н
L	L	L	н	н	Н	н	н	Н	H	н	н	H	L	Н	Н	Н	н	Н	Н	Н	н
L	L	H	L.	L	L	н	Н	Н	Н	Н	Н	Н	Н	L	Н	Н	Н	Н	н	Н	Н
L	L	Н	L	L	н	н	Н	Н	Н	Н	н	Н	н	Н	L	H	н	н	н	н	Н
L		H	L	H	L	H	Н	Н	Н	Н	Ħ	H	H	14	ł ŧ	L	+1	Н	н	H	Н
L	L	Н	L	н	Н	Н	Н	Н	Н	Н	Н	Н	H	Н	Н	H	L	H	н	H	H
L	L	Н	Н	L	L	Н	Н	Н	Н	н	H	н	н	н	н	н	н	L	Н	н	н
L	ᆫ	H	Н	L	Н	Н	Н	H	Н	н	Н	H	Н	Н	Н	Н	Н	н	L	Н	Н
L	L	Н	Н	Н	L	Н	Н	Н	Н	Н	Н	H	Н	Н	Н	Н	н	Н	H	L	н
L	L	Н	Н	Н	Н	н	Н	н	H	Н	Н	н	Н	Н	Н	Н	н	н	н	н	L
L	н	×	Х	Х	X	н	Н	H	Н	Н	Н	Н	H	Н	н	н	Н	Н	Н	н	н
Н	L	×	×	X	×	Н	Н	Н	H	Н	Н	Н	H	Н	Н	н	Н	Н	Н	н	Н
Ħ	н	Х	X	X	Х	Н	Н	Н	Н	Н	H	Н	Н	Н	Н	H	H	Н	Н	Н	Η

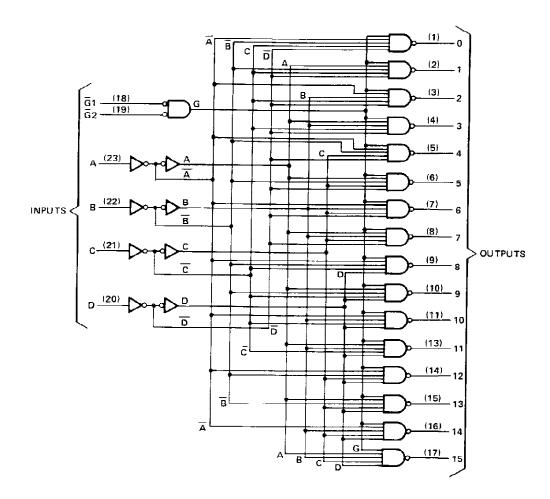
H = high level, L = low level, X = Irrelevant

schematics of inputs and outputs





logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)											7 V
Input voltage											
Operating free-air temperature range: SN54154 Circuits									-55	°C to	125°C
SN74154 Circuits			,						, ()°C 1	o 70°C
Storage temperature range									-65	C to	150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		SN54154				SN74154			
	MII	N I	NOM	MAX	MIN	NOM	MAX	UNIT	
Supply voltage, VCC	4.	.5	5	5.5	4.75	5	5.25	٧	
High-level output current, IOH				-800			-800	μА	
Low-level output current, IOL				16			16	mA	
Operating free-air temperature, TA	-5	55		125	0	-	70	С	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	O A CAMETER	Transpuritionat	,	SN5415	4		SN7415	4	
	PARAMETER	TEST CONDITIONS [†]	MIN	TYP	MAX	MIN	TYP‡	MAX	UNIT
V_{IH}	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.8			0.8	V
VIK	Input clamp voltage	V _{CC} = MIN, I _I = -12 mA			-1.5			-1.5	V
V _{OH}	High-level output voltage	V _{CC} = MIN. V _{IH} = 2 V. V _{IL} = 0.8 V, I _{OH} = -800 μA	2.4	3.4		2.4	3.4		V
VOL	Low-level output voltage	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = 0.8 V, I _{OL} = 16 mA		0.2	0.4		0.2	0.4	V
Ιį	Input current at maximum input voltage	V _{CC} = MAX. V _I = 5.5 V	1		1			1	mΑ
łін	High-level input current	V _{CC} = MAX, V _I = 2.4 V			40			40	μA
1 ₁ L	Low-level input current	V _{CC} = MAX, V _I = 0.4 V			-1.6			-1.6	mΑ
los	Short-circuit output current §	V _{CC} = MAX	-20		-55	18		-57	mΑ
Icc	Supply current	V _{CC} = MAX, See Note 2		34	49		34	56	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type. $^{\ddagger}_{c}$ All typical values are at V_{CC} = 5 V, TA = 25 °C.

switching characteristics, VCC = 5 V, TA = 25°C

	PARAMETER	TEST CONDITION	JS MIN	V TYP	MAX	UNIT
tPLH	Propagation delay time, low-to-high-level output, from A, B, C, or D inputs through 3 levels of logic			24	36	าร
^t PH L	Propagation delay time, high-to-low-level output, from A, B, C, or D inputs through 3 levels of logic	C _L - 15 pF, R _L - 40	ο Ω,	22	33	ns
^t PLH	Propagation delay time, low-to-high-level output, from either strobe input	See Note 3		20	30	175
tPHL	Propagation delay time, high-to-low-level output, from either strobe input			18	27	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



Not more than one output should be shorted at a time, NOTE 2: $I_{\mbox{CC}}$ is measured with all inputs grounded and all outputs open.

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